TOSHIBA 2SC2099

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 2 0 9 9

2~30MHz SSB LINEAR POWER AMPLIFIER APPLICATIONS (LOW SUPPLY VOLTAGE USE)

Specified 12.5V, 28MHz Characteristics

Output Power : $Po = 20W_{PEP}$ (Min.) Power Gain : $G_p = 12dB$ (Min.) Collector Efficiency : $\eta_{\rm C} = 35\%$ (Min.) Intermodulation Distortion : IMD = -30dB (Max.)

MAXIMUM RATINGS ($Tc = 25^{\circ}C$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	V _{CBO}	40	V
Collector-Emitter Voltage	VCES	40	V
Collector-Emitter Voltage	VCEO	18	V
Emitter-Base Voltage	$V_{ m EBO}$	4	V
Collector Current	$I_{\mathbf{C}}$	6	A
Collector Power Dissipation	$P_{\mathbf{C}}$	60	W
Junction Temperature	Tj	175	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-65~175	°C

Unit in mm Ø9.8 MAX 184±015 2.45±0.25 **EMITTER** 1. BASE **EMITTER** 4. COLLECTOR **JEDEC EIAJ TOSHIBA** 2-10H1A

Weight: 4.0g

ELECTRICAL CHARACTERISTICS (Tc = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector-Emitter Breakdown Voltage	V (BR) CEO	$I_{C} = 50 \text{mA}, I_{B} = 0$	18	_	_	V
Collector-Emitter Breakdown Voltage	V _(BR) CES	$I_C=50$ mA, $V_{EB}=0$	40	_	_	V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	$I_E=1mA$, $I_C=0$	4	_	_	V
DC Current Gain	${ m h_{FE}}$	$V_{CE}=5V, I_{C}=5A$ *	20	_	185	
Transition Frequency	${ m f_T}$	$V_{\text{CE}} = 5V$, $I_{\text{C}} = 0.5A$		100		MHz
Collector Output Capacitance	C _{ob}	$V_{CB} = 12.5V, I_{E} = 0$ f = 1MHz	1	_	250	pF
Power Gain	G_p	$V_{CC} = 12.5V, f_1 = 28.000$	12.0		l	dB
Input Power	Pi	MHz, $f_2 = 28.001 \text{MHz}$		_	1.2	W_{PEP}
Collector Efficiency	$\eta_{\mathbf{C}}$	$I_{ m idle}$ = 25mA	35	45	1	%
Intermodulation Distortion	IMD	$Po = 20W_{PEP}$ (Fig.)		_	-30	dB
Series Equivalent Input Impedance	Z _{in}	V _{CC} =12.5V, f ₁ =28.000 MHz, f ₂ =28.001MHz		1.1 -j0.25		Ω
Series Equivalent Output Impedance	Z _{out}	Po=20W _{PEP}	_	3.0 - j0.75	_	Ω

^{*} Pulse Test: Pulse Width $\leq 100 \mu$ s, Duty Cycle $\leq 3\%$

CAUTION

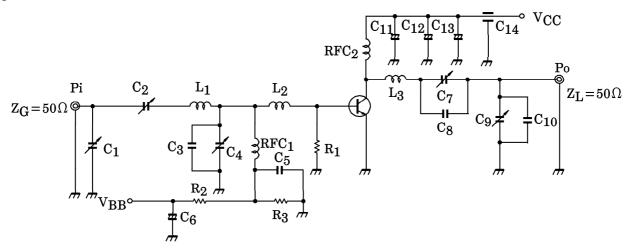
Beryllia Ceramics is used in this product. The dust or vapor can be dangerous to humans. Do not break, cut, crush or dissolve chemically. Dispose of this product properly according to law. Do not intermingle with normal industrial or domestic waste.

961001EAA2

TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

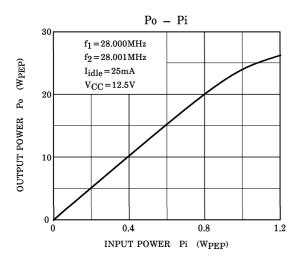
TOSHIBA 2SC2099

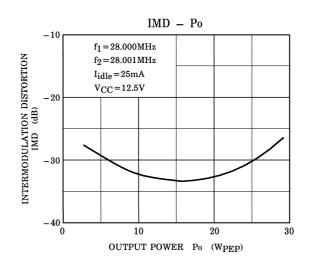
Fig. Pi TEST CIRCUIT



 $\begin{array}{ccc} C_{13} & : & 0.04 \mu F \\ C_{14} & : & 1000 p F \end{array}$

(FEED THROUGH)





CAUTION

These are only typical curves and devices are not necessarily guaranteed at these curves.

961001EAA2

The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.

The information contained herein is subject to change without notice.